

$p_{\text{T}}^{\text{miss}}$ bin (GeV)	Post-fit background yield (events)	Observed yield (events)
300–450	233.2 ± 10.7	237
450–600	64.4 ± 3.8	67
600–800	22.5 ± 2.5	20
800–1000	3.3 ± 0.8	3
1000–1200	1.0 ± 0.5	3
> 1200	0.4 ± 0.3	1